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(54) **STABILIZATION OF OUTPUT TIMING DELAY**

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CPC **H03K 19/018521** (2013.01); **H03K 19/00384** (2013.01)

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USPC ..... 327/108  
See application file for complete search history.

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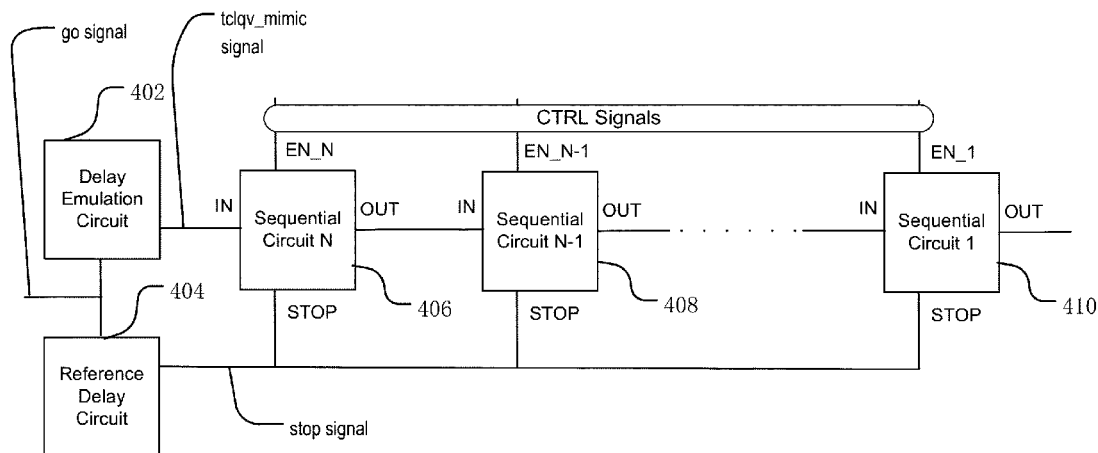
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(57) **ABSTRACT**

An integrated circuit includes an output buffer and a control circuit. The output buffer has a signal input, a signal output, and a set of control inputs. The output buffer has an output buffer delay, and a driving strength adjustable in response to control signals applied to the set of control inputs. Alternatively, the output buffer delay is variable. The control circuit is connected to the set of control inputs of the output buffer. The control circuit uses first and second timing signals to generate the control signals, and can include a first delay circuit that generates the first timing signal with a first delay, and a second delay circuit that generates the second timing signal with a second delay that correlates with the output buffer delay.

**16 Claims, 17 Drawing Sheets**



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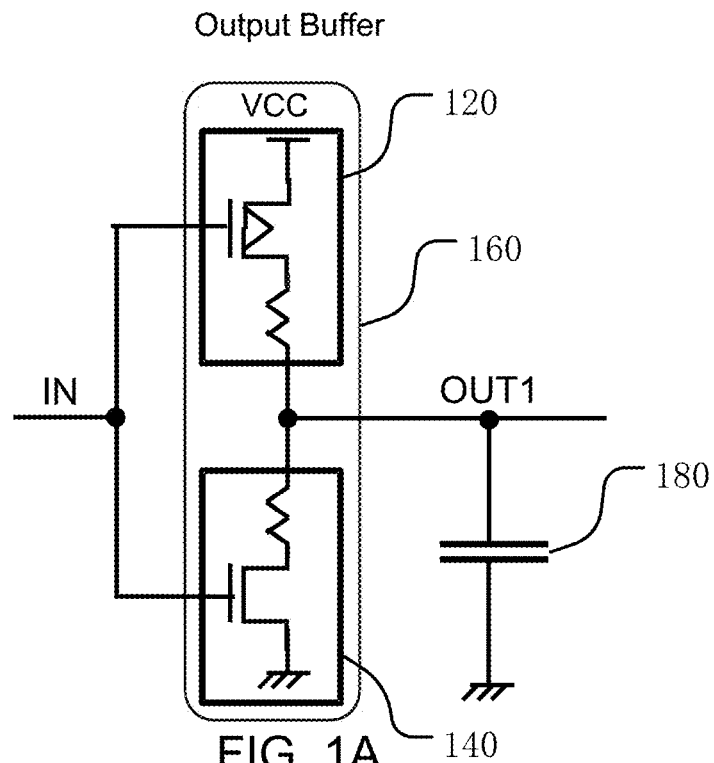


FIG. 1A  
Prior art

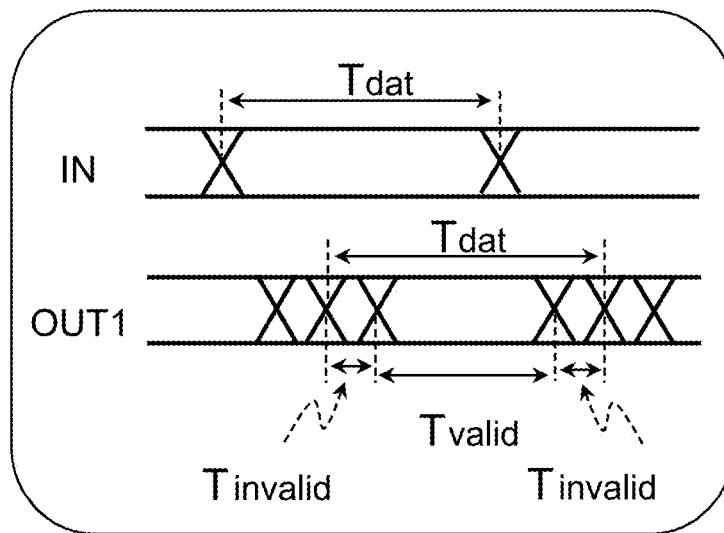


FIG. 1B  
Prior art

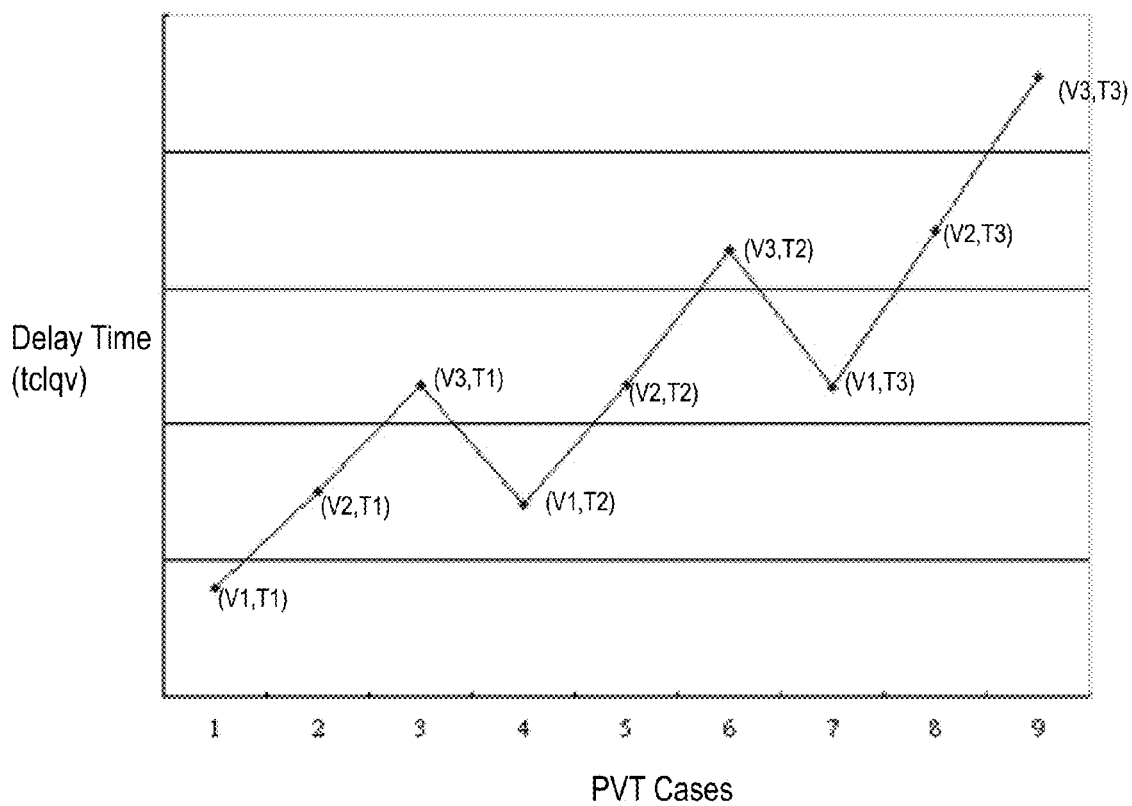


FIG. 2  
Prior art

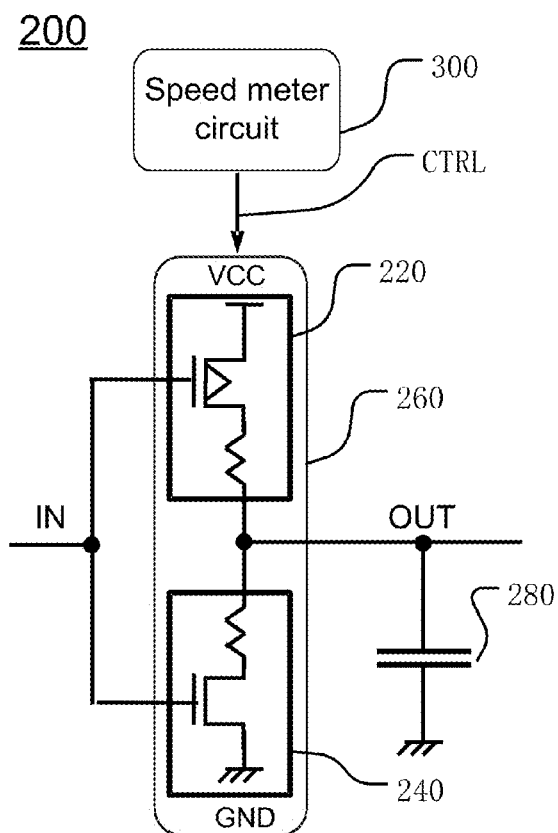


FIG. 3A

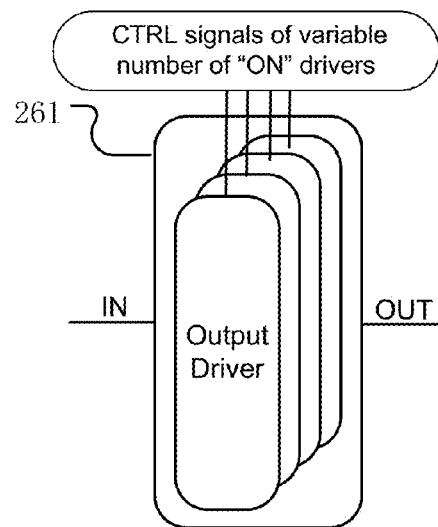


FIG. 3B

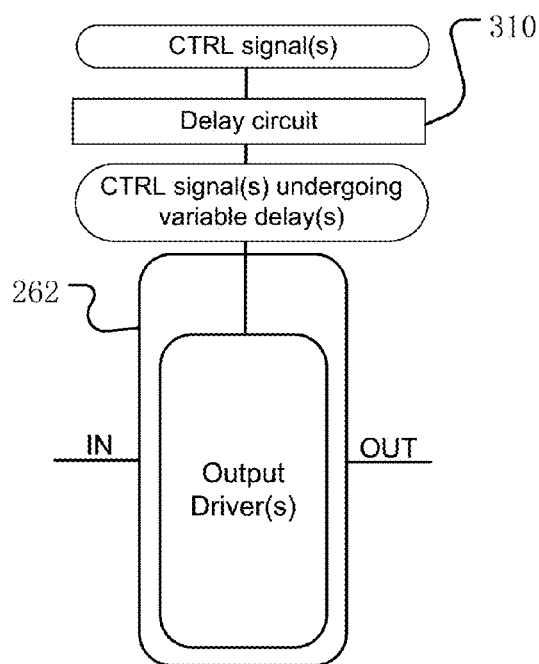


FIG. 3C

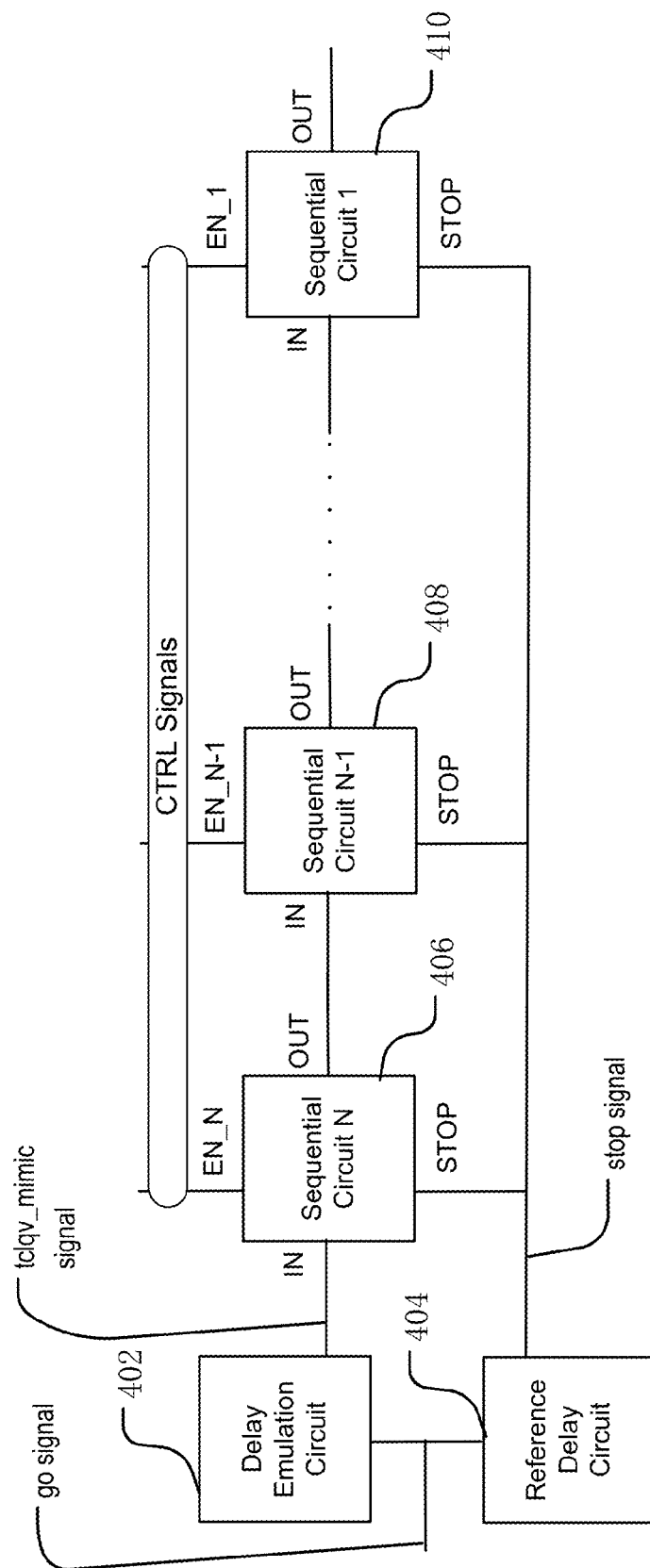


FIG. 4

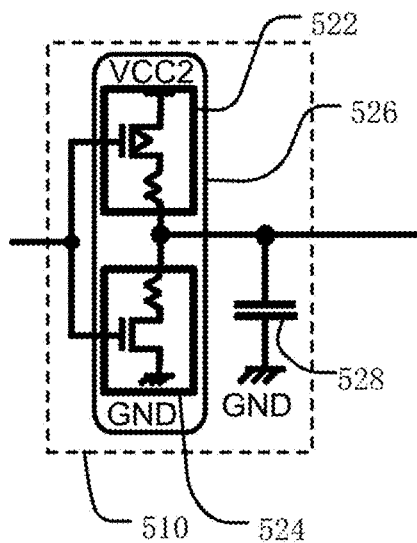


FIG. 5

## Reference Delay Circuits

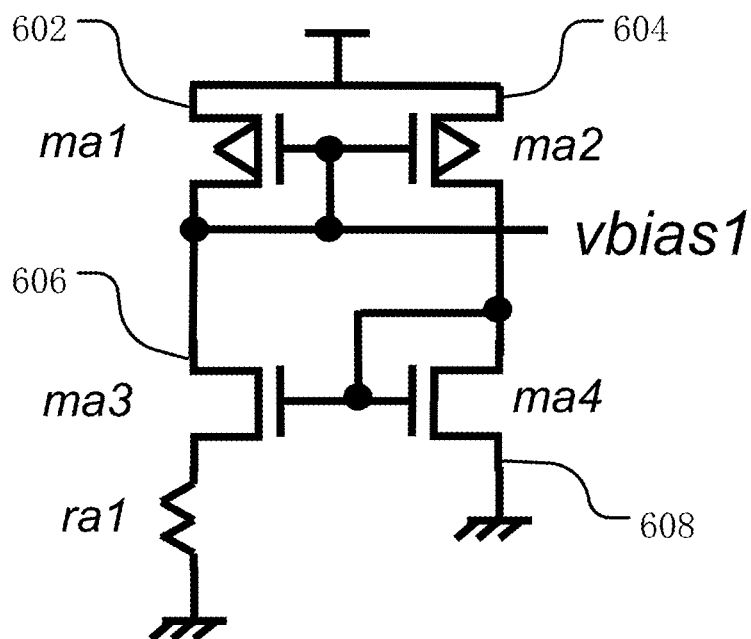


FIG. 6

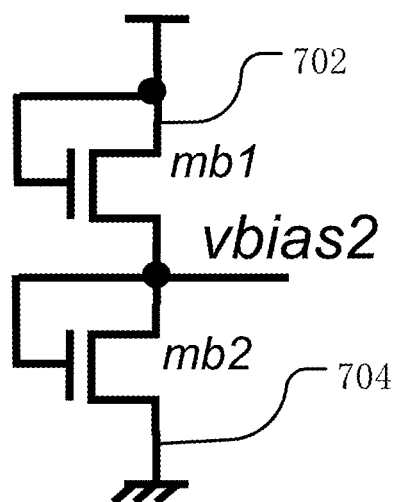


FIG. 7



Reference  
Delay Circuits

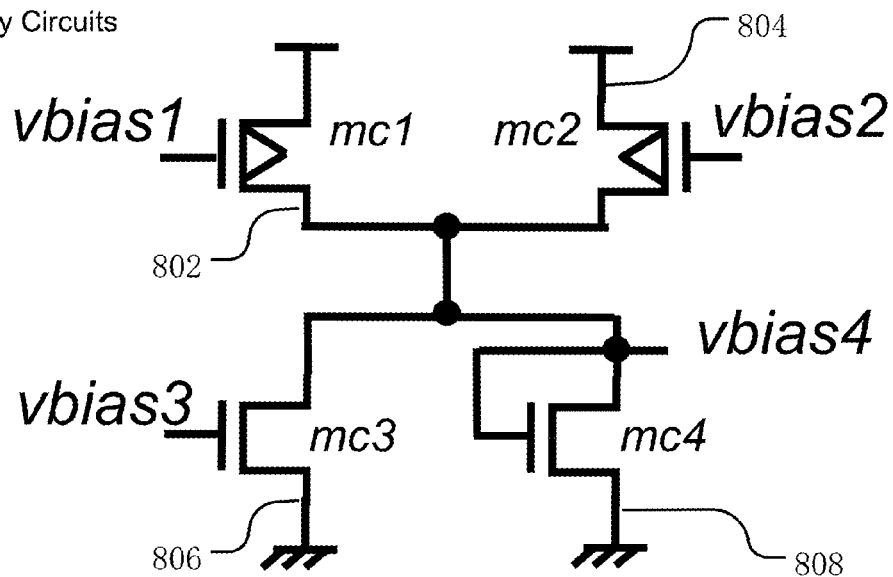


FIG. 8

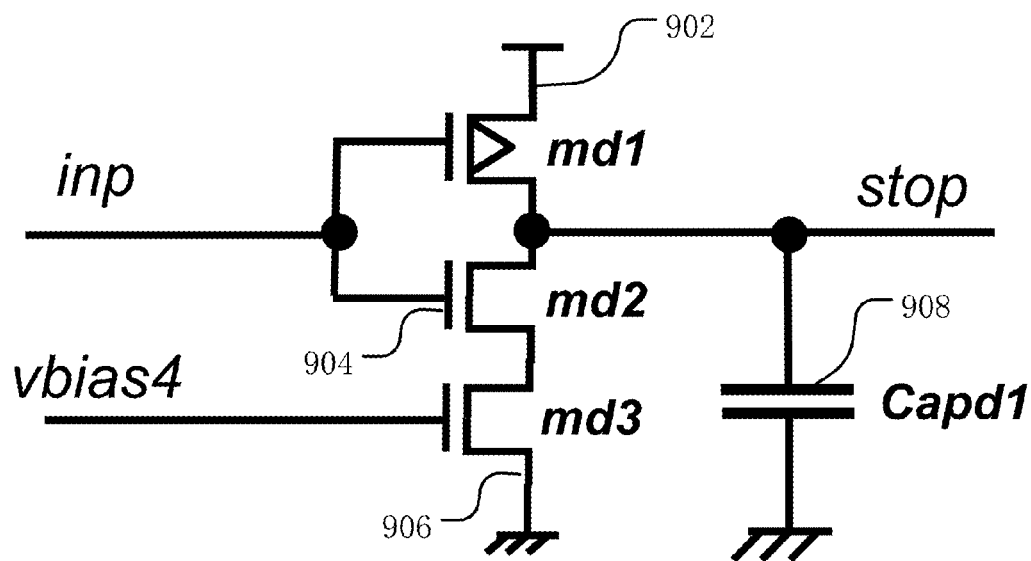


FIG. 9

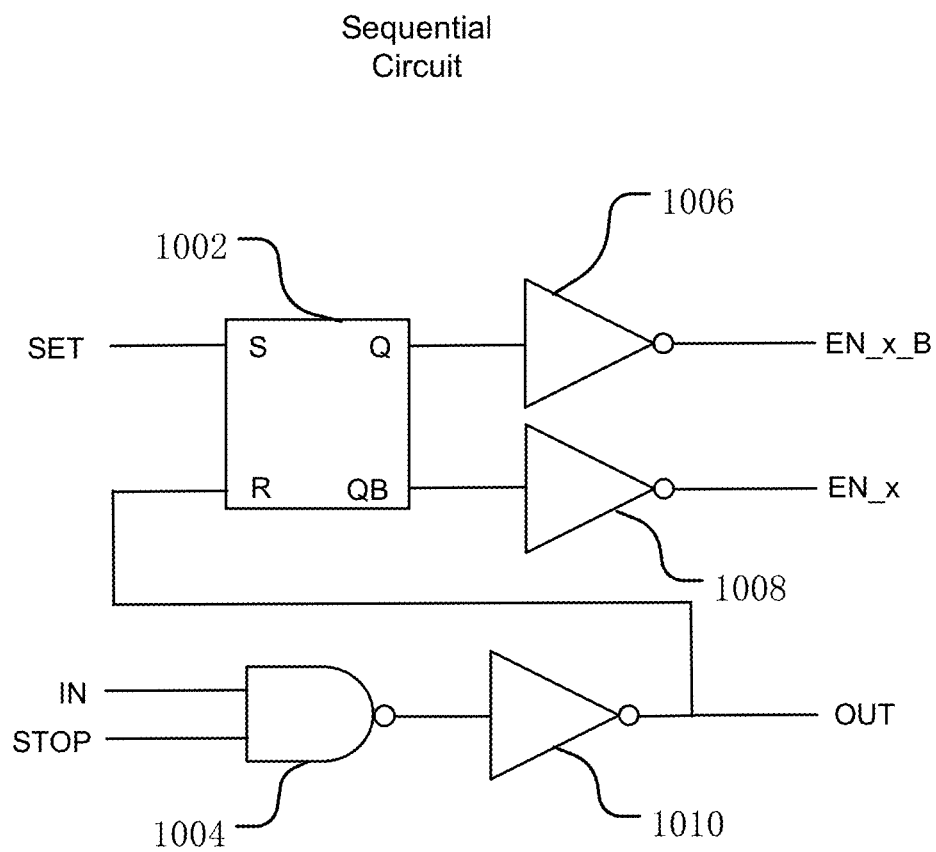


FIG. 10

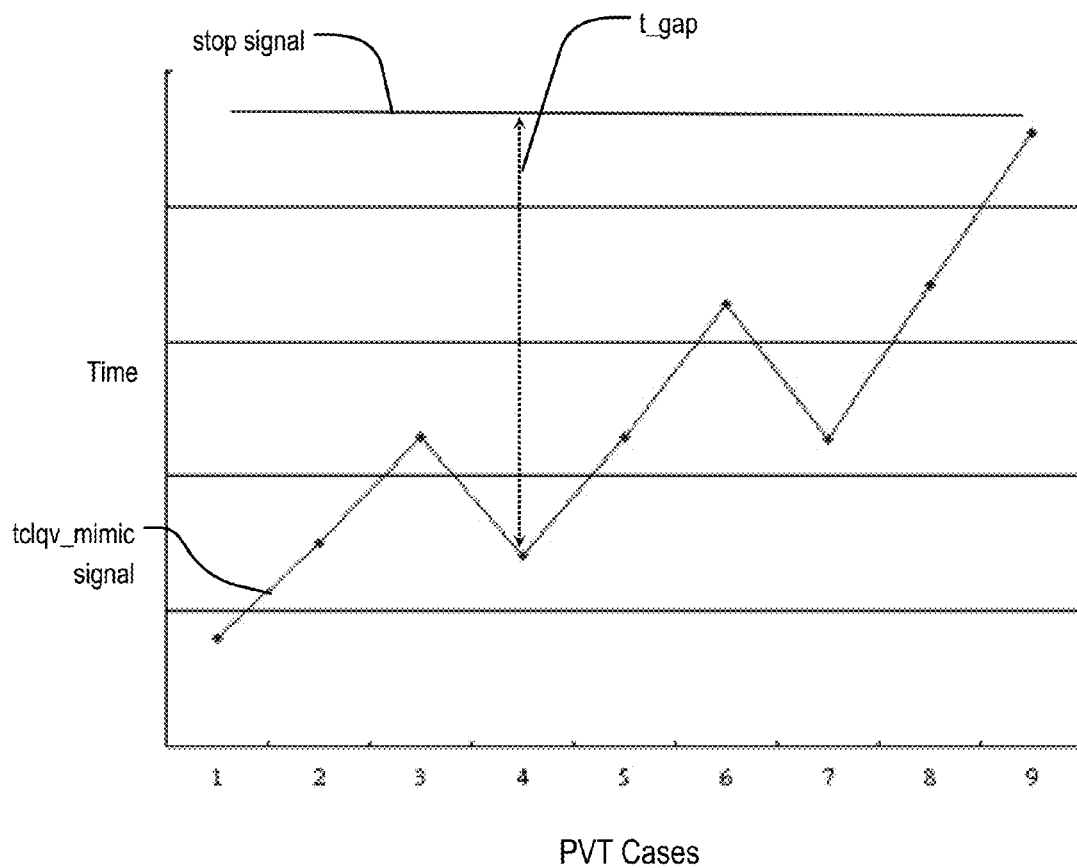


FIG. 11

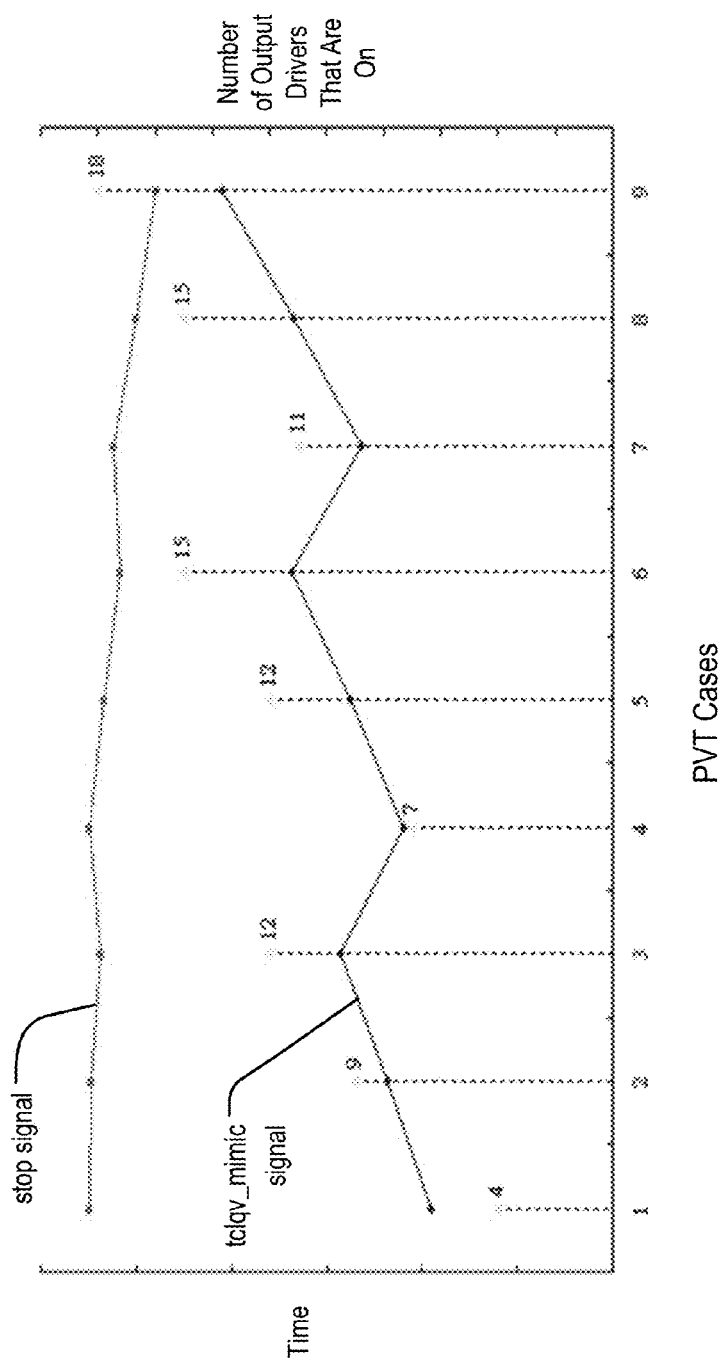


FIG. 12

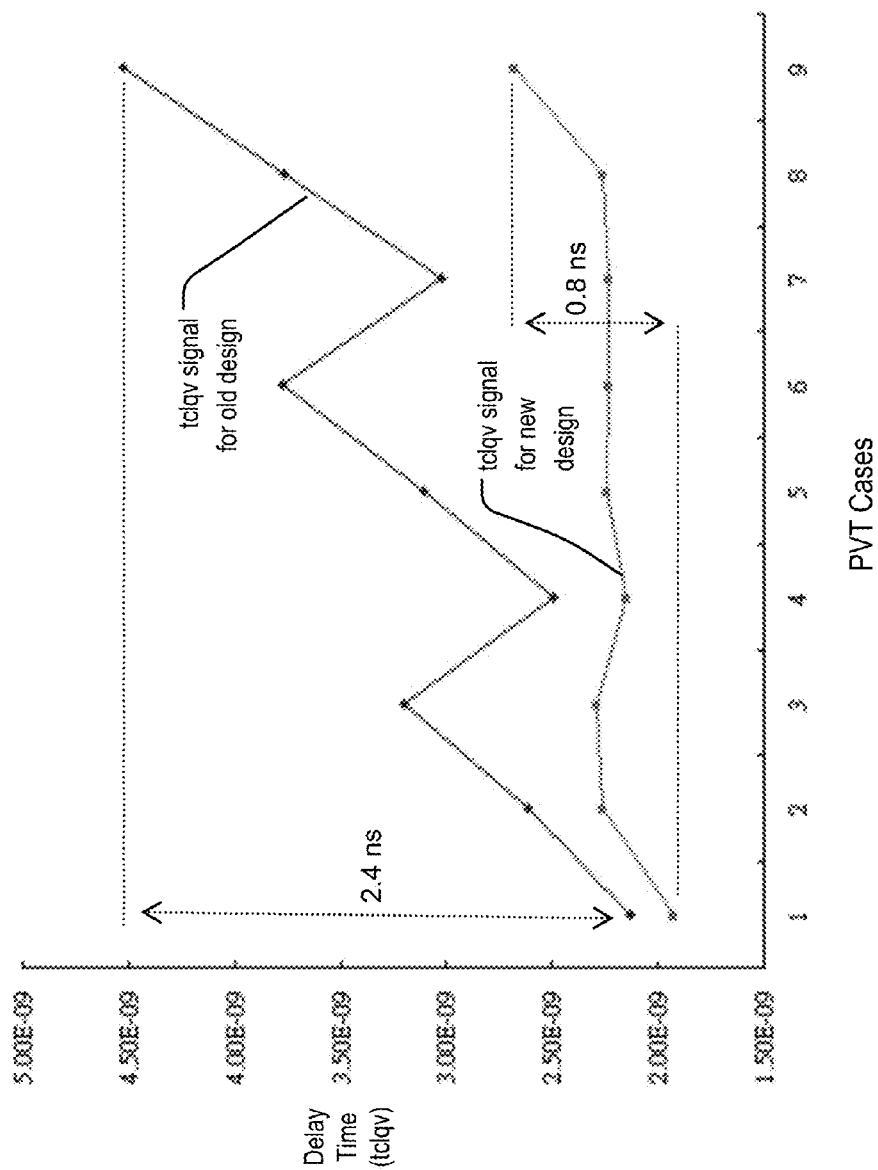


FIG. 13

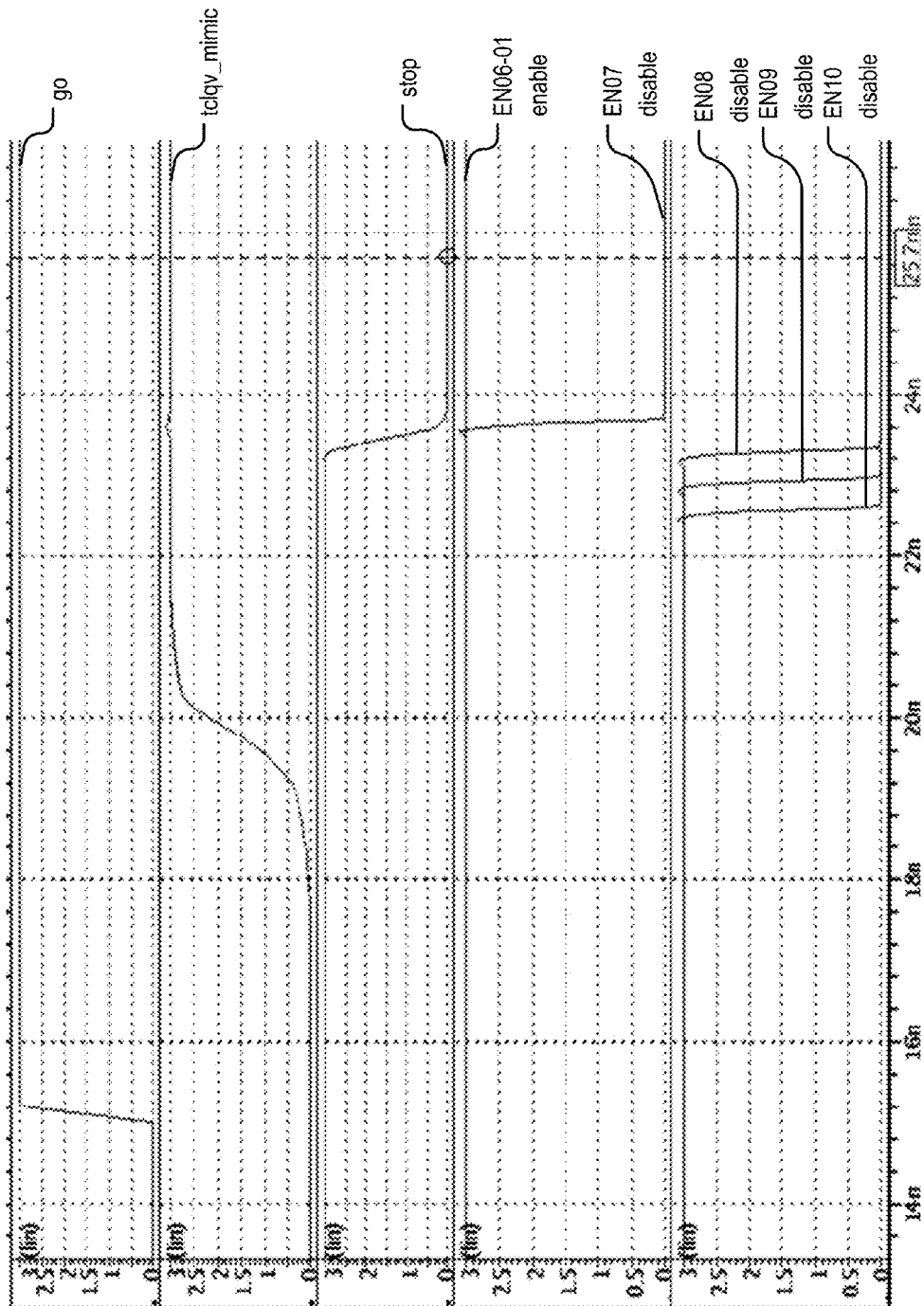


FIG. 14

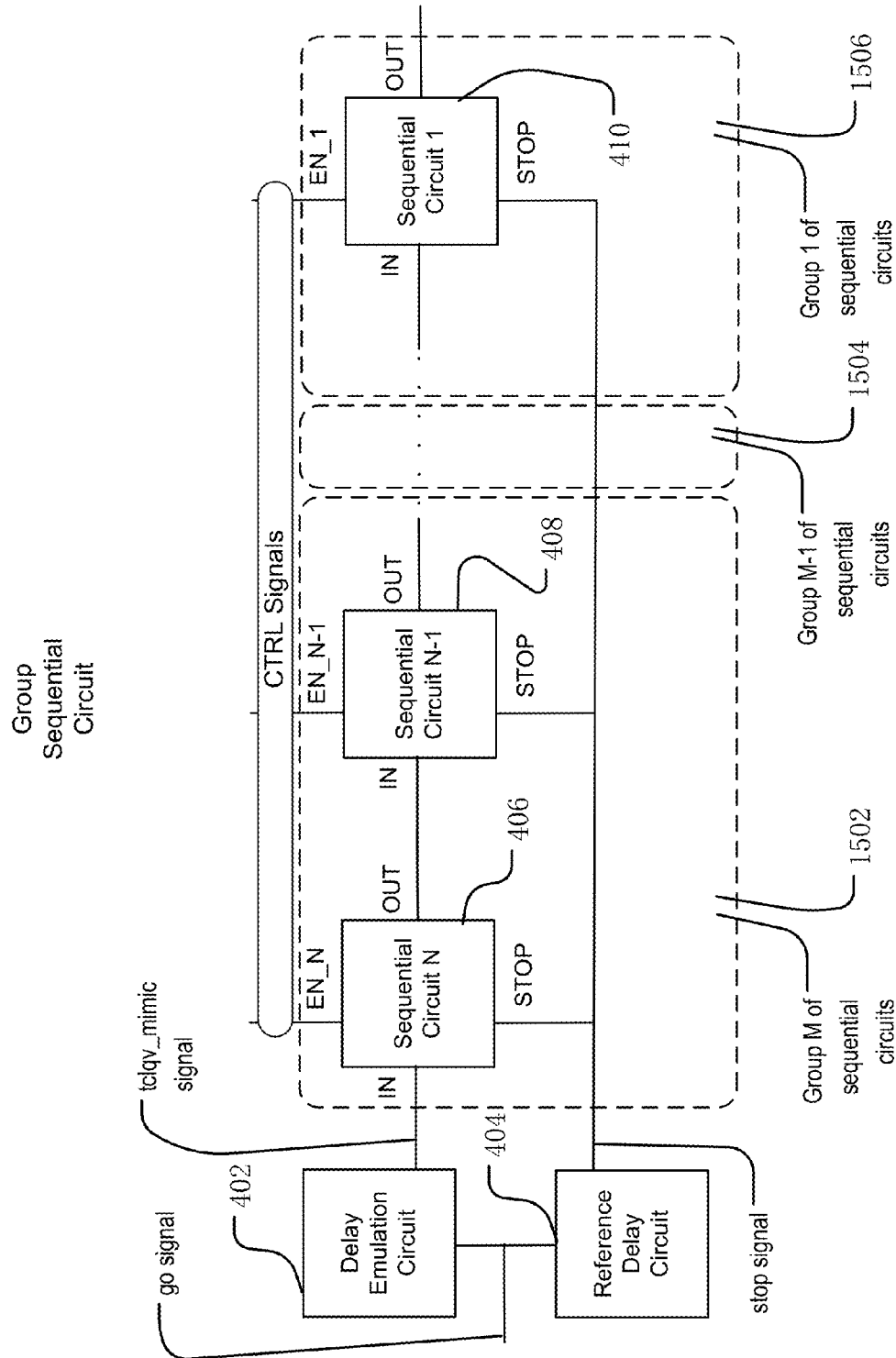


FIG. 15

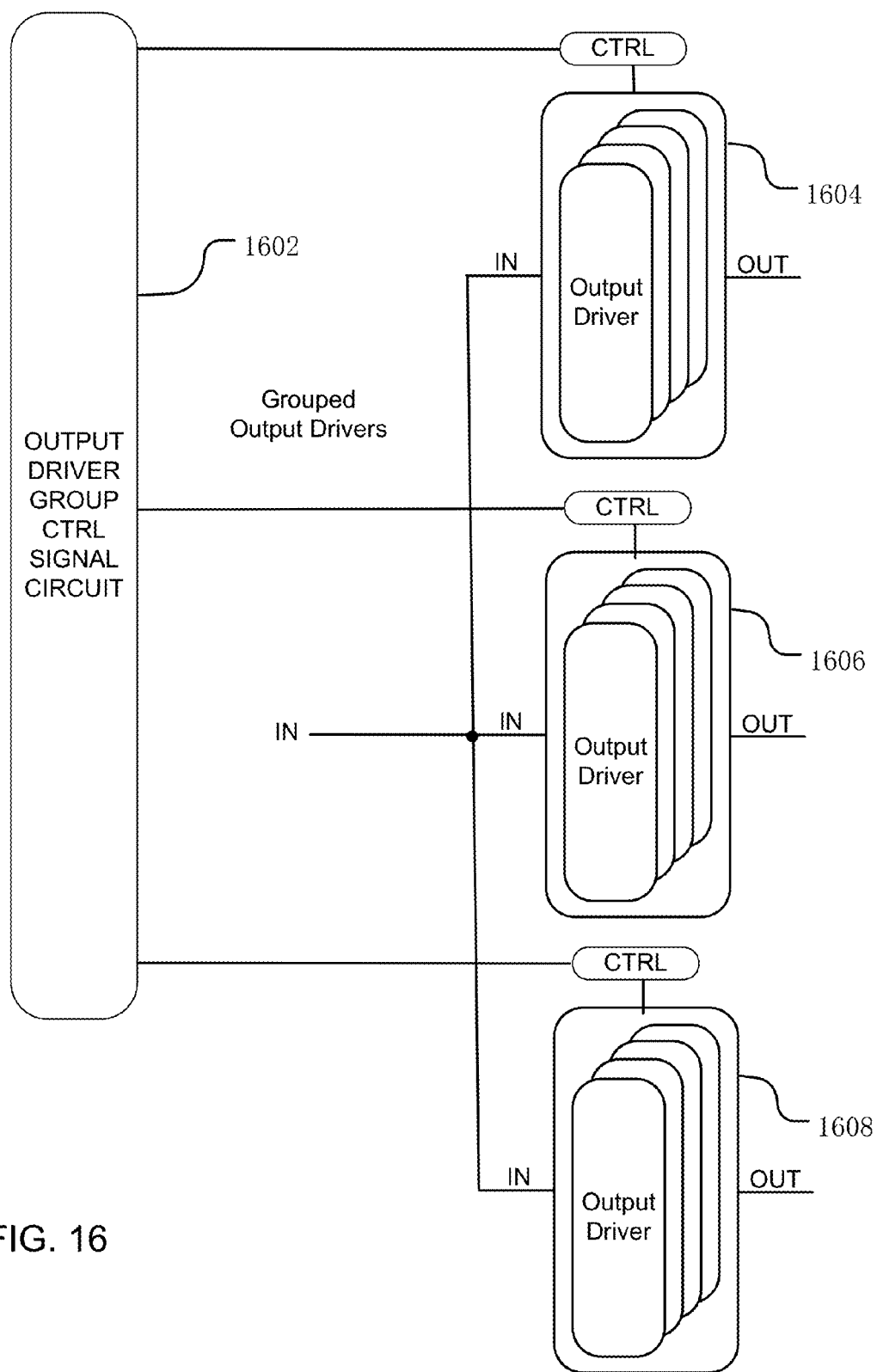


FIG. 16



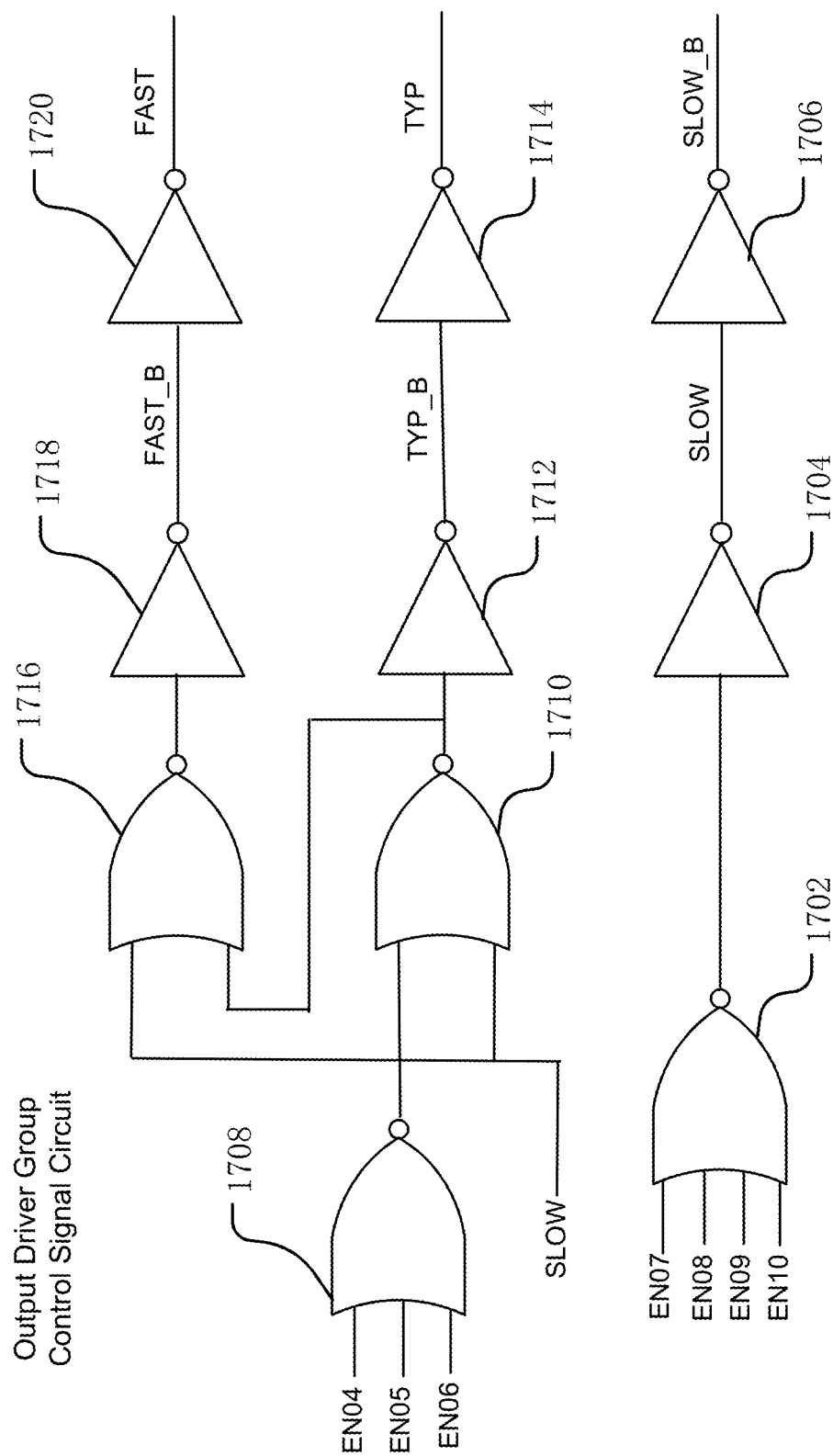
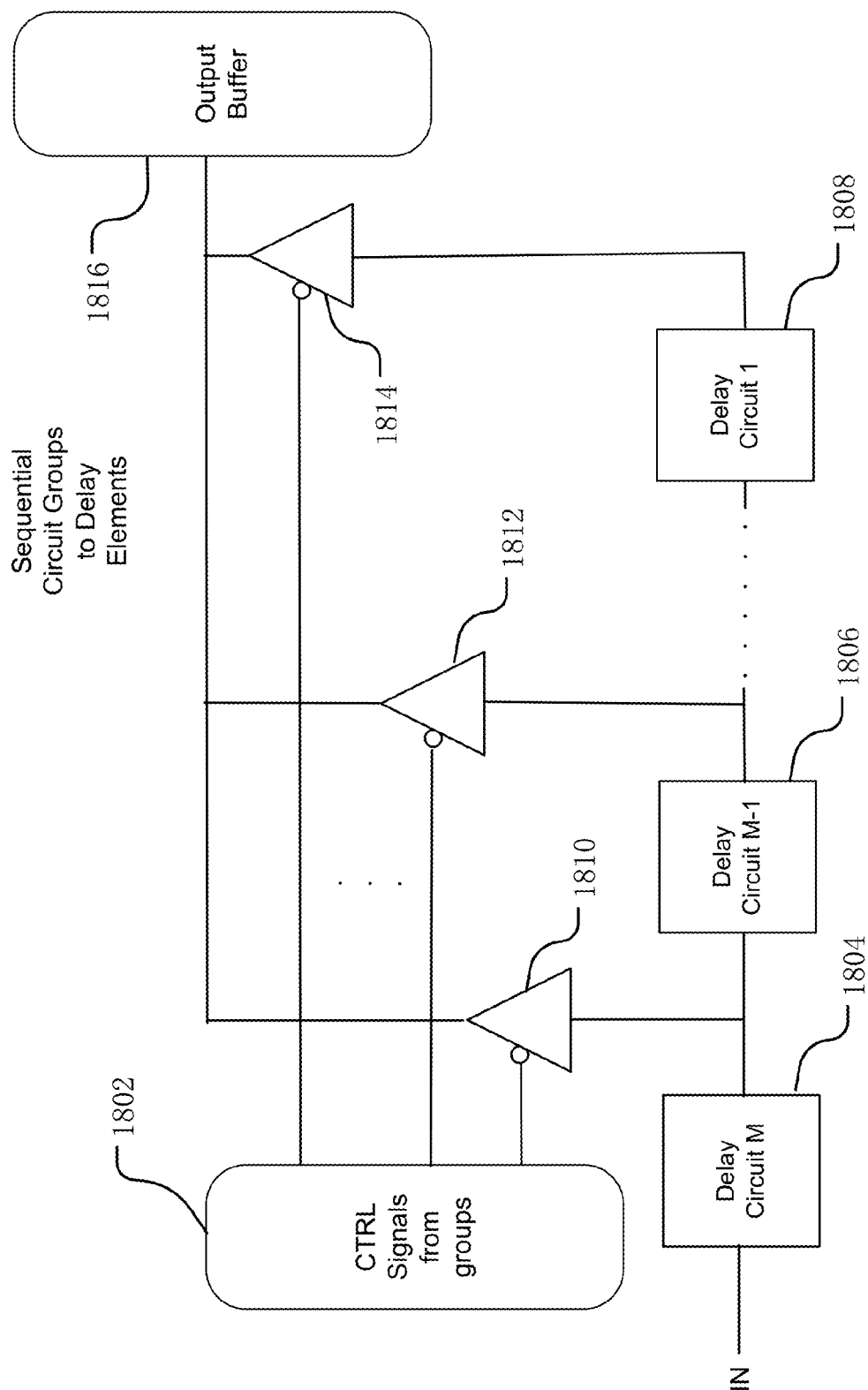


FIG. 17



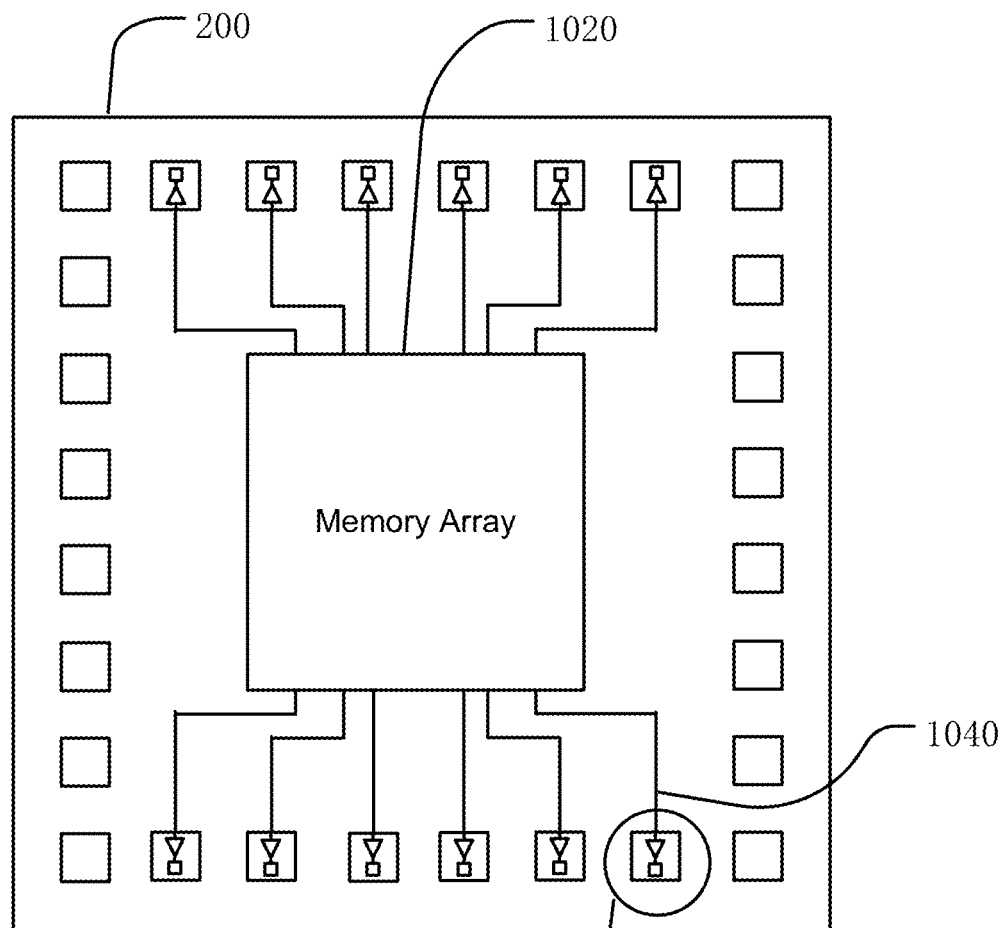
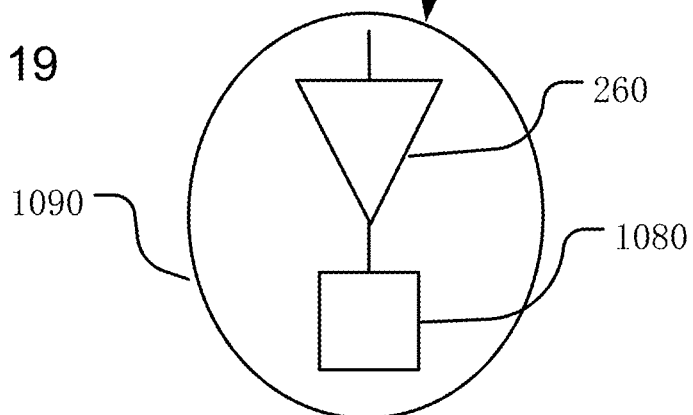


FIG. 19



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## STABILIZATION OF OUTPUT TIMING DELAY

### BACKGROUND

#### 1. Field of the Invention

The present technology relates to digital circuits and more particularly to output buffers of digital circuits.

#### 2. Description of Related Art

An output buffer in an integrated circuit may be used to receive internal data at low current levels and present it to external loading at higher current levels. The output timing of the output buffer may vary with process corners, voltages, and temperatures (PVT). Variations in output timing due to PVT conditions may reduce the data valid window. The higher the operating speed, the more likely the reduced data valid window may affect the performance and even the reliability of the integrated circuit.

One known output buffer is described in U.S. Pat. No. 8,643,404, directed to "Self-Calibration of Output Buffer Driving Strength". In the '404 Patent, the output driving strength is changed iteratively, where the result of any iterative change results in either a "stronger" or "weaker" driving strength. If the initial driving strength is far off, then reaching the ideal driving strength may require multiple iterations.

It is desirable to provide an output buffer that is substantially insensitive to PVT conditions and thus provide reliable performance for high speed operations of integrated circuits, and have good results for consistent output buffer timing delay, with a less iterative approach to reaching an ideal output buffer timing delay.

### SUMMARY

One aspect of the technology is an integrated circuit comprising an output buffer, a plurality of sequential circuits, and a control circuit.

The output buffer has an output buffer delay, a signal input and a signal output. The output buffer has a variable number of a plurality of output drivers that are on, in response to output driver control signals.

The plurality of sequential circuits receive as input first and second timing signals, and relative timing of the first and second timing signals determines the variable number of output drivers. In one embodiment, the first timing signal is generated from a first delay circuit. In one embodiment, the second timing signal is generated with a second delay that correlates with the output buffer delay. The variable number of output drivers can depend on a number of the sequential circuits transited by the second timing signal until the plurality of sequential circuits receive the first timing signal.

The control circuit performs the actions of: (i) using the first delay circuit to generate the first timing signal with a first delay, (ii) using a second delay circuit to generate the second timing signal with the second delay that correlates with the output buffer delay, (iii) using the plurality of sequential circuits to generate the output driver control signals, and (iv) causing the variable number of the plurality of output drivers to be on, in response to the output driver control signals.

Another aspect of the technology is an integrated circuit comprising an output buffer, a plurality of sequential circuits, a plurality of delay circuits, and a control circuit.

The output buffer has an output buffer delay, a signal input and a signal output, and a control signal input receiving an output driver control signal.

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The plurality of sequential circuits receive as input first and second timing signals. The first timing signal is generated from a first delay circuit. The second timing signal is generated with a second delay that correlates with the output buffer delay.

The plurality of delay circuits generate a variable delay determining the output buffer delay. The variable delay depends on a number of the plurality of sequential circuits transited by the second timing signal until the plurality of sequential circuits receive the first timing signal.

The control circuit performs the actions of: (i) using the first delay circuit to generate the first timing signal with a first delay, (ii) using a second delay circuit to generate the second timing signal with the second delay that correlates with the output buffer delay, (iii) using the plurality of sequential circuits to generate the output driver control signal, and (iv) causing the output driver control signal to undergo the variable delay in order to reach the output buffer.

Another aspect of the technology is a method for controlling an output buffer, where the output buffer has an output buffer delay. The method includes:

- generating a first timing signal with a first delay;
- generating a second timing signal with a second delay that correlates with the output buffer delay; and
- adjusting a variable number of output drivers that are on in a plurality of output drivers in the output buffer, in response to a number of sequential circuits of a plurality of sequential circuits transited by the first timing signal upon receipt by the plurality of sequential circuits of the first timing signal.

Another aspect of the technology is a method for controlling an output buffer, where the output buffer has an output buffer delay. The method includes:

- generating a first timing signal with a first delay;
- generating a second timing signal with a second delay that correlates with the output buffer delay;
- adjusting a variable delay of a plurality of delay circuits in response to a number of sequential circuits of a plurality of sequential circuits transited by the first timing signal upon receipt by the plurality of sequential circuits of the first timing signal; and
- causing an output buffer control signal to undergo the variable delay in order to reach the output buffer.

In various embodiments of the technology, delay circuits in the plurality of delay circuits include a series of inverters.

In various embodiments of the technology, the output buffer delay depends on the variable delay generated by the plurality of delay circuits.

In various embodiments of the technology, sequential circuits in the plurality of sequential circuits include a flip-flop and combinational logic.

In various embodiments of the technology, the first delay circuit responds to a reference signal to generate the first timing signal with the first delay, and the first delay is substantially insensitive to at least one of process, voltage and temperature (PVT) conditions. The second delay circuit responds to the reference signal on its input to generate the second timing signal on its output with the second delay, and the second delay correlates with changes in the output buffer delay resulting from said at least one of process, voltage and temperature (PVT) conditions.

In various embodiments of the technology, the plurality of output drivers are in parallel, and the output buffer delay is shortened or lengthened by the variable number of output drivers being more or less.

In various embodiments of the technology, the plurality of output drivers are divided into a plurality of groups of output drivers, and a same sequential circuit driver in the plurality of sequential circuits controls different output drivers within a same group of the plurality of groups of output drivers. In a further embodiment of the technology, the plurality of sequential circuits are divided into a plurality of groups of sequential circuits, and different sequential circuits in a same group of the plurality of groups of sequential circuits control the same group of the plurality of groups of output drivers.

In various embodiments of the technology, the plurality of sequential circuits are divided into a plurality of groups of sequential circuits, and different sequential circuits in a same group of the plurality of groups of sequential circuits control a same output driver in the plurality of output drivers.

In various embodiments of the technology, the plurality of sequential circuits are divided into a plurality of groups of sequential circuits, and a same delay is generated by the plurality of delay circuits responsive to different sequential circuits within a same group of the plurality of groups of sequential circuits.

In various embodiments of the technology, the plurality of sequential circuits are divided into a plurality of groups of sequential circuits, and the variable delay is a same value caused by output driver signals generated from different sequential circuits within a same group of the plurality of groups of sequential circuits.

Other aspects and advantages of the present technology can be seen on review of the drawings, the detailed description and the claims, which follow.

#### BRIEF DESCRIPTION OF THE DRAWINGS

FIG. 1A is an example design of an output buffer.

FIG. 1B illustrates waveforms associated with the output buffer in FIG. 1A.

FIG. 2 is a graph of the varying buffer delay under various conditions.

FIG. 3A is a block diagram of an example integrated circuit including output buffers having an output buffer delay controlled by a speed meter circuit.

FIG. 3B illustrates an output buffer with control signals that control a variable number of output drivers that are "on".

FIG. 3C illustrates an output buffer with at least one control signal undergoing at least one variable delay.

FIG. 4 is a block diagram of a speed meter circuit used in the integrated circuit in FIG. 3A.

FIG. 5 is a block diagram of a delay emulation circuit used in FIG. 4.

FIGS. 6-9 are circuit diagrams for parts of a reference delay circuit used in FIG. 4.

FIG. 10 is a circuit diagram of an example sequential circuit in the speed meter circuit of FIG. 4.

FIG. 11 is a graph of delays for signals from the delay emulation circuit and an ideal reference delay circuit.

FIG. 12 is a graph of delays for signals from the delay emulation circuit and the reference delay circuit, and the number of output drivers that are on, for different PVT cases.

FIG. 13 is a graph of delays, showing the improvement of the new output buffer.

FIG. 14 is a graph of signal traces in the speed meter circuit in FIG. 4.

FIG. 15 is a block diagram of a speed meter circuit as in FIG. 4, with the sequential circuits organized into groups.

FIG. 16 illustrates an output buffer of 3B, with the output drivers organized into groups.

FIG. 17 is an example control signal circuit for the output buffer of FIG. 16.

FIG. 18 is an example variable delay circuit for the output buffer of FIG. 16, responsive to the control signal circuit FIG. 17.

FIG. 19 is a chip diagram of an example integrated circuit.

#### DETAILED DESCRIPTION

A detailed description of implementations of the present technology is provided with reference to the Figures. Preferred implementations are described to illustrate the present technology, not to limit its scope, which is defined by the claims. Those of ordinary skill in the art will recognize a variety of equivalent variations on the description that follows.

FIG. 1A is an example design of an output buffer 160. The output buffer 160 includes an NMOS transistor 140 and a PMOS transistor 120 in series. The NMOS transistor 140 has a control terminal, a drain terminal and a source terminal connected to a ground potential. The PMOS transistor 120 has a control terminal, a drain terminal and a source terminal connected to a fixed reference voltage VCC. An input signal IN is coupled to the control terminals of both transistors 120 and 140 in parallel. An output signal OUT1 is coupled to the drain terminals of both transistors 120 and 140. A capacitor 180 represents external loading to the output buffer 160.

FIG. 1B illustrates waveforms associated with the output buffer 160 in FIG. 1A. Waveforms are shown for the input signal IN, and the output signal OUT1. Tdat is the data valid window of the input signal IN. Under certain PVT conditions, the output buffer 160 may provide the same data valid window Tdat for the output signal OUT1 as the data valid window of the input signal IN. However, under other PVT conditions in which at least one of the process, voltage and temperature conditions is changed, driving strength of the output buffer 160 may decrease/increase, prolong/accelerate rising and falling edges of pulses in the output signal OUT1, and thus reduce the data valid window for the output signal OUT1 from Tdat to Tvalid. Tvalid is narrower than Tdat by the amount of twice Tinvalid because for each pulse, its rising edge is reduced by Tinvalid and its falling edge is also reduced by Tinvalid.

FIG. 2 is a graph of the varying buffer delay under various conditions. The buffer delay is measured at combinations of different supply voltages V1, V2, V3, and different temperatures T1, T2, T3. V1 is greater than V2 which is greater than V3. T3 is greater than T2 which is greater than T1.

FIG. 3A is a block diagram of an example integrated circuit 200 including output buffers having an output buffer delay controlled by a speed meter circuit. The example integrated circuit 200 includes an output buffer 260, and a speed meter circuit 300. The output buffer 260 has a signal input, a signal output, and a set of control inputs. The output buffer 260 has an output buffer delay adjustable in response to control signals CTRL applied to the set of control inputs. An input signal IN is coupled to the signal input of the output buffer 260. An output signal OUT is coupled to the signal output of the output buffer 260. A capacitor 280 is coupled to the signal output of the output buffer 260, representing capacitive loading to the output buffer 260.

The output buffer delay of the output buffer 260 is adjustable. FIGS. 3B and 3C show different embodiments of the output buffer of FIG. 3A.

FIG. 3B illustrates an output buffer with control signals that control a variable number of output drivers that are "on". The control signals CTRL from the speed meter circuit

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enable or disable selected output drivers to adjust the driving strength of the output buffer **260**, which in turn adjusts the output buffer delay. The more output drivers which are on, the shorter the output buffer delay. The fewer output drivers which are on, the longer the output buffer delay. The input signal IN is provided to the plurality of parallel output drivers. Further description about how the control signals CTRL select output drivers is provided in connection with FIG. 4.

The output buffer **261** includes a plurality of output drivers. Each output driver in the output buffer **261** includes a first transistor **240**, and a second transistor **220**. The first transistor **240** in an output driver has a first conduction terminal electrically coupled to a first fixed reference voltage GND, a second conduction terminal electrically coupled to the output terminal of the output buffer **261**, and a control terminal electrically coupled to the input terminal of the output buffer **261**. The first transistor **240** has a first channel type, and in one implementation, includes an NMOS (N-channel metal-oxide-semiconductor) transistor.

The second transistor **220** in an output driver has a first conduction terminal electrically coupled to the fixed reference voltage VCC, a second conduction terminal electrically coupled to the output terminal of the output buffer **261**, and a control terminal electrically coupled to the input terminal of the output buffer **261**. The second transistor has a second channel type opposite the first channel type, and in one implementation, includes a PMOS (P-channel metal-oxide-semiconductor) transistor.

Resolution of driving strength, and thus resolution of output buffer delay, depends on the number of output drivers in each output buffer **261**. A higher number of output drivers corresponds to higher resolution. With four output drivers, the output buffer **261** has four steps in driving strength and thus output buffer delay. With sixteen output drivers, the output buffer **261** has sixteen steps in driving strength and thus output buffer delay, assuming equally sized drivers. In other embodiments, the driver sizes can vary, for example including a 1× driver, a 2× driver, a 4× driver and an 8× driver, and decoding circuitry can be used to select a combination of drivers that most effectively adjusts the total driving strength and thus adjusts the output buffer delay. Also, in other embodiments, the drivers can have strengths that are adjustable using analog control signals, such that the total output buffer delays is adjustable using the analog control signals.

FIG. 3C illustrates an output buffer with at least one control signal undergoing at least one variable delay.

At least one control signal CTRL from the speed meter circuit enables or disables one or more selected ungrouped output drivers or group of output drivers. The control signal undergoes variable delay via delay circuit **310**. Following processing by the delay circuit **310**, the control signal, which has undergone a variable delay, is provided to at least one output driver or group of output drivers. Further description about how the control signal CTRL is delayed is provided in connection with FIG. 18.

Unlike the output buffer **261** in FIG. 3B, the output buffer **262** in FIG. 3C can include one ungrouped output driver or one group of output drivers, rather than multiple output drivers or multiple groups of output drivers. A group of output drivers are controlled together as a unit, such that the output drivers in the same group are collectively on or off.

In another embodiment, features of FIGS. 3B and 3C are combined, such that control signals control multiple ungrouped output drivers or multiple groups of output drivers, that undergo variable delay in a delay circuit.

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FIG. 4 is a block diagram of a speed meter circuit used in the integrated circuit in FIG. 3A.

A go signal is sent at the same time to delay emulation circuit **402** and reference delay circuit **404**. Timing signals are generated with amounts of delay that are different between delay emulation circuit **402** and reference delay circuit **404**. Delay emulation circuit **402** generates the tclqv\_mimic timing signal following a delay which correlates with the output buffer delay. An example delay emulation circuit is shown in FIG. 5. Reference delay circuit **404** generates the stop timing signal following a delay which is substantially insensitive to at least one of process, voltage and temperature (PVT) conditions. An example reference delay circuit is shown in FIGS. 6-9.

The tclqv\_mimic timing signal is received by the plurality of sequential circuits, including sequential circuit N **406**, sequential circuit N-1 **408**, and sequential circuit 1 **410**. The tclqv\_mimic timing signal propagates sequentially through the IN and OUT terminals of each sequential circuit in the plurality of sequential circuits, until the plurality of sequential circuits receives the stop timing signal from reference delay circuit **404**. A variable number of sequential circuits is transited by the tclqv\_mimic timing signal until the plurality of sequential circuits receives the stop timing signal from reference delay circuit **404** at the STOP terminal coupled in parallel to the reference delay circuit **404**. This variable number of sequential circuits is an indication of the difference between the tclqv\_mimic and stop timing signals.

As each sequential circuit is transited by the tclqv\_mimic timing signal, each transited sequential circuit generates an EN\_# signal (or alternatively, a disable signal). For example, when the tclqv\_mimic timing signal transits sequential circuit N **406**, sequential circuit N **406** generates the EN\_N signal. When the tclqv\_mimic timing signal transits sequential circuit N-1 **408**, sequential circuit N-1 **408** generates the EN\_N-1 signal. When the tclqv\_mimic timing signal transits sequential circuit 1 **410**, sequential circuit 1 **410** generates the EN\_1 signal.

The various EN\_# signals indicate whether a corresponding output driver is off. As more sequential circuits are transited sequentially by the tclqv\_mimic timing signal until the stop timing signal is received by the plurality of sequential circuits, more of the corresponding output drivers are off.

FIG. 5 is a block diagram of a delay emulation circuit used in FIG. 4.

A scaled-down circuit **526** of the output buffer **260** inside the delay emulation circuit **510** includes a first scaled-down circuit **524** of the first transistor **240** of the output buffer **260**, and a second scaled-down circuit **522** of the second transistor **220** of the output buffer **260**.

The first scaled-down circuit **524** has a first conduction terminal electrically coupled to the first fixed reference voltage GND, a second conduction terminal electrically coupled to the output terminal of the delay emulation circuit **510**, and a control terminal electrically coupled to the input terminal of the delay emulation circuit **510**. The second scaled-down circuit **522** has a first conduction terminal electrically coupled to the second fixed reference voltage VCC2, a second conduction terminal electrically coupled to the output terminal of the delay emulation circuit **510**, and a control terminal electrically coupled to the input terminal of the delay emulation circuit **510**. For convenience of design, the second fixed reference voltage VCC2 may be the same as the fixed reference voltage VCC for the output buffer **260** (FIG. 3A). Alternatively, the second fixed reference voltage VCC2 may be different than the fixed reference

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voltage VCC for the output buffer 260, provided that the delay emulation circuit 510 can emulate the behavior of the output buffer 260 (FIG. 3A).

The first scaled-down circuit 524 and the second scaled-down circuit 522 in the delay emulation circuit 510 include a scaled-down NMOS transistor and a scaled-down PMOS transistor, emulating the first transistor 240 and the second transistor 220 in the output buffer 260, respectively.

The delay emulation circuit 510 also includes a capacitor 528 coupled to the output terminal of the delay emulation circuit 510. The capacitor 528 has a capacitive value scaled down from capacitive loading at the output terminal of the output buffer 260, as represented by the capacitor 280 (FIG. 3A), and with a resistance scaled up such that the RC delay of the scaled-down circuit 526 emulates the RC delay of the output buffer 260.

FIGS. 6-9 are circuit diagrams for parts of a reference delay circuit used in FIG. 4.

The circuit in FIG. 6 compensates for temperature variation such that the stop timing signal generated by the reference delay circuit is substantially insensitive to temperature.

P-type transistors ma1 602 and ma2 604 have sources coupled to a supply reference voltage, and gates and drains all coupled together to an output node generating vbias1. N-type transistors ma3 606 and ma4 608 have gates and drains coupled together to the output node generating vbias1. N-type transistor ma3 606 has a source coupled to a ground reference voltage through resistance ra1. N-type transistor ma4 608 has a source coupled to a ground reference voltage. The signal vbias1 from the output node compensates for temperature variations in the stop timing signal generated by the reference delay circuit.

The circuit in FIG. 7 compensates for supply voltage variation such that the stop timing signal generated by the reference delay circuit is substantially insensitive to supply voltage.

N-type transistors mb1 702 and mb2 704 are coupled in series between a supply reference voltage and a ground reference voltage. N-type transistors mb1 702 and mb2 704 are diode connected, with gate and drain coupled together. An output node generating vbias 2 is coupled to the source of n-type transistor mb1 702 and to the drain of n-type transistor mb2 704. A supply reference voltage is coupled to the drain of n-type transistor mb1 702. A ground reference voltage is coupled to the source of n-type transistor mb2 704. The signal vbias2 from the output node compensates for supply voltage variations in the stop timing signal generated by the reference delay circuit.

The circuit in FIG. 8 adds compensation for process corner variation such that the stop timing signal generated by the reference delay circuit is substantially insensitive to process corner.

P-type transistors mc1 802 and mc2 804 have sources coupled to a supply reference voltage, and gates and drains coupled together to an output node generating vbias4. P-type transistor mc1 802 has a gate coupled to vbias 1 from FIG. 6. P-type transistor mc2 804 has a gate coupled to vbias2 from FIG. 7. N-type transistors mc3 806 and mc4 808 have drains coupled together to the output node generating vbias4 and sources coupled to a ground reference voltage. N-type transistor mc3 806 has a gate coupled to vbias3 from a fixed voltage such as a bandgap reference. N-type transistor mc4 808, is diode connected, with gate and drain coupled together. The signal vbias4 from the output node compensates for temperature variations, supply voltage variations,

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and process corner variations in the stop timing signal generated by the reference delay circuit.

The circuit in FIG. 9 generates the stop timing signal which is substantially insensitive to temperature variations, supply voltage variations, and process corner variations.

P-type transistor md1 902 and n-type transistors md2 904 and md3 906 are coupled in series between the supply voltage reference and the ground voltage reference. P-type transistor md1 902 and n-type transistor md2 904 are coupled together like an inverter. P-type transistor md1 902 and n-type transistor md2 904 have gates coupled together to an input node to receive an input inp such as the go signal of FIG. 4, and drains coupled together to an output node generate an output such as the stop signal of FIG. 4. N-type transistor md3 906 has a gate coupled to vbias4 from FIG. 8, a source coupled to the ground voltage reference, and a drain coupled to the source of n-type transistor md2 904. Capacitor capd1 908 is coupled to the output node. The stop timing signal is substantially insensitive to temperature variations, supply voltage variations, and process corner variations.

FIG. 10 is a circuit diagram of an example sequential circuit in the speed meter circuit of FIG. 4.

NAND gate 1004 receives as inputs a stop timing signal such as in FIG. 4 and an IN signal. The stop timing signal is received from a reference delay circuit in parallel together with other sequential circuits. The IN signal is received from the OUT signal of the preceding sequential circuit. The IN signal of the first sequential circuit in the plurality of sequential circuits is the tclqv\_mimic timing signal from the delay emulation circuit of FIG. 4.

Inverter 1010 has an input coupled to the output of NAND gate 1004 and an output generating the OUT signal. If the IN signal goes high prior to the stop timing signal changing from high to low, the OUT signal is high; this corresponds to the tclqv\_mimic signal transiting the sequential circuits and the transited sequential circuits turning off corresponding output drivers via the EN\_x output or EN\_x\_B output. If the IN signal goes high after the stop timing signal changes from high to low, then the OUT signal is low; this corresponds to any subsequent sequential circuits causing the corresponding output drivers to stay turned on via the EN\_x output or EN\_x\_B output. SR latch 1002 has an S input receiving a SET signal and an R input receiving the OUT signal. Inverter 1006 has an input coupled to the Q output of SR latch 1002 and an output generating the EN\_x\_B signal. Inverter 1008 has an input coupled to the QB output of SR latch 1002 and an output generating the EN\_x signal. Examples traces of such output are shown in FIG. 14.

In other embodiments, the sequential circuits are a sequence of circuits such that an output of a prior sequential circuit is coupled to an input of a subsequent sequential circuit. Different sequential circuits can share the same components with each other, such as the same combinational logic and/or the same state logic such as flip-flops.

FIG. 11 is a graph of delays for signals from the delay emulation circuit and an ideal reference delay circuit.

The tclqv\_mimic timing signal is generated from the delay emulation circuit of FIG. 4. The tclqv\_mimic signal emulates the dependency on varying supply voltage and/or varying temperature and/or varying process. Accordingly, the tclqv\_mimic timing signal varies substantially with varying supply voltage and/or varying temperature and/or varying process.

By contrast, the stop timing signal is compensated for varying supply voltage, varying temperature, and varying

process. Accordingly, the stop timing signal remains substantially constant despite varying supply voltage and/or varying temperature and/or varying process.

The value `t_gap` indicates the varying difference between the `tlqv_mimic` and stop timing signals. The speed meter circuit of FIGS. 3A and 4 measures `t_gap` in order to maintain an output buffer delay that is substantially constant despite variations in temperature, supply voltage, and/or process corner.

FIG. 12 is a graph of delays for signals from the delay emulation circuit and the reference delay circuit, and the number of output drivers that are on, for different PVT cases.

The `tlqv_mimic` timing and stop timing signals are discussed in connection with FIG. 12. The number on the graph corresponding to the vertical axis on the right of the graph indicates the number of output drivers that are on.

If the `tlqv_mimic` signal has a relatively high value, the emulated buffer delay is relatively long, such that the output buffer is expected to be relatively slow unless corrected. Accordingly, the speed meter circuit measurement results in turning on relatively more output drivers to reduce the actual output buffer delay to a more repeatable value despite variations in temperature, supply voltage, and/or process corner.

If the `tlqv_mimic` signal has a relatively low value, the emulated buffer delay is relatively short, such that the output buffer is expected to be relatively fast unless corrected. Accordingly, the speed meter circuit measurement results in turning on relatively few output drivers to increase the actual output buffer delay to a more repeatable value despite variations in temperature, supply voltage, and/or process corner.

FIG. 13 is a graph of delay, showing the improvement of the new output buffer.

For an old design without the speed meter circuit as disclosed herein, the output buffer delay has a range that is 2.5 nanoseconds wide across variations in temperature and supply voltage.

By contrast, in an embodiment with the speed meter circuit as disclosed herein, the output buffer delay has a range that is 0.8 nanoseconds wide across variations in temperature and supply voltage.

FIG. 14 is a graph of signal traces in the speed meter circuit in FIG. 4.

Initially, the go signal is sent to the delay emulation circuit and reference delay circuit as in FIG. 4. In response to the go signal, the delay emulation circuit generates the `tlqv_mimic` timing signal after a delay which correlates with the output buffer delay.

The `tlqv_mimic` timing signal then transits the plurality of sequential circuits. When sequential circuit 10 is transited, sequential circuit 10 generates the EN10 disable signal. When sequential circuit 09 is transited, sequential circuit 09 generates the EN09 disable signal. When sequential circuit 08 is transited, sequential circuit 08 generates the EN08 disable signal. When sequential circuit 07 is transited, sequential circuit 07 generates the EN07 disable signal.

In response to the go signal, the reference delay circuit generates the stop timing signal after a delay which is substantially insensitive to at least one of process, voltage and temperature (PVT) conditions. The stop timing signal is received in parallel by the plurality of sequential circuits. In response to the stop timing signal, no further disable signals are generated by the plurality of sequential circuits. The remaining sequential circuits 06-01 continue to generate respective EN\_# signals, from EN06 through EN01. As a

result, output drivers corresponding to sequential circuits 10-07 are off, and output drivers corresponding to sequential circuits 06-01 are on.

FIG. 15 is a block diagram of a speed meter circuit as in FIG. 4, with the sequential circuits organized into groups.

The plurality of sequential circuits is grouped into M groups. In this example, group M includes sequential circuit N 406 and sequential circuit N-1 408, group 1 1506 includes sequential circuit 1 410, and any intermediate groups such as group M-1 1504 include any intermediate sequential circuits. Grouping has the advantage of reducing layout area and current consumption of a large number of control signals from the individual sequential circuits, to a smaller number of control signals from the groups of sequential circuits. Reduced granularity of the output buffer delay is a cost of grouping.

FIG. 16 illustrates an output buffer of 3B, with the output drivers organized into groups.

In the output buffer of FIG. 16, output drivers are grouped into output driver groups 1604, 1606, and 1608. In one example, output driver group 1604 is on or off depending on the control signals from group M in FIG. 15, output driver group 1606 is on or off depending on the control signals from group M-1 in FIG. 15, and output driver group 1608 is on or off depending on the control signals from group 1 in FIG. 15. The number of output drivers within a particular output driver group may be just one output driver, or multiple output drivers. The number of output drivers may be the same across the different output driver groups, or may be different. Output driver group control signal circuit 1602 processes the control signals from the individual sequential circuits in FIG. 15, such that a single output driver group control signal is generated by a single group of sequential circuits, and such that one output driver group is on at a time.

In an alternative embodiment, multiple output driver groups are on at one time such that their respective driving strengths are combined.

As discussed in connection with FIG. 17, output driver groups 1604, 1606, and 1608 are each on or off depending on the corresponding one of the SLOW, TYP, and FAST output driver group control signals. The output driver group controlled by the FAST output driver group control signal has the fewest number of output drivers, the smallest output drivers, or some combination of few and slow. The output driver group controlled by the SLOW output driver group control signal has the largest number of output drivers, the largest output drivers, or some combination of largest number and largest. The output driver group controlled by the TYP output driver group control signal has the medium number of output drivers, the medium size output drivers, or some combination of medium number and medium size.

FIG. 17 is an example control signal circuit for the output buffer of FIG. 16. This output driver group control signal circuit processes the control signals from the individual sequential circuits in FIG. 15, such that a single output driver group control signal is generated by a single group of sequential circuits which includes multiple sequential circuits, and such that one output driver group is on at a time.

NOR gate 1702 receives as inputs the signals EN07, EN08, EN09, EN10 from the sequential circuits of group M 1502 in FIG. 15. Inverter 1704 has an input coupled to the output of NOR gate 1702, and an output generating the SLOW output driver group control signal. Inverter 1706 has an input coupled to the output of inverter 1704 and an output generating SLOW\_B which is the complement of SLOW.

So long as at least one of EN07, EN08, EN09, EN10 is high, the SLOW output driver group control signal is high.



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When all of EN07, EN08, EN09, EN10 are low, the SLOW output driver group control signal is low and SLOW\_B is high. So until the last sequential circuit in group M 1502 is transited by the tclqv\_mimic signal, the SLOW output driver group control signal is high. After the last sequential circuit in group M 1502 is transited by the tclqv\_mimic signal, the SLOW output driver group control signal is low.

NOR gate 1708 receives as inputs the signals EN04, EN05, EN06 from the sequential circuits of group M-1 1504 in FIG. 15. NOR gate 1710 receives as inputs the output of NOR gate 1708 and the SLOW output driver group control signal. Inverter 1712 has an input coupled to the output of NOR gate 1708, and an output generating TYP\_B which is the complement of TYP. Inverter 1714 has an input coupled to the output of inverter 1712 and an output generating TYP output driver group control signal.

While the SLOW output driver group control signal is high, the TYP output driver group control signal is low. In this embodiment, a single output driver group control signal is high. If the SLOW output driver group control signal turns low, then the TYP output driver group control signal is high so long as at least one of EN04, EN05, EN06 is high. When all of EN04, EN05, EN06 are low, the TYP output driver group control signal is low and TYP\_B is high. So after group M 1502 in FIG. 15 is transited by the tclqv\_mimic signal, and until the last sequential circuit in group M-1 1504 is transited by the tclqv\_mimic signal, the TYP output driver group control signal is high. After the last sequential circuit in group M-1 1504 is transited by the tclqv\_mimic signal, the TYP output driver group control signal is low.

NOR gate 1716 receives as inputs the SLOW output driver group control signal and the TYP output driver group control signal. Inverter 1718 has an input coupled to the output of NOR gate 1716, and an output generating FAST\_B which is the complement of FAST. Inverter 1720 has an input coupled to the output of inverter 1718 and an output generating FAST output driver group control signal.

While either the SLOW output driver group control signal is high, or the TYP output driver group control signal is high, the FAST output driver group control signal is low. The FAST output driver group control signal turns high after the TYP output driver group control signal turns low (by which time the SLOW output driver group control signal has turned low already). In this embodiment, a single output driver group control signal is high. Inputs from the last sequential circuits EN03, EN02, EN01 are unnecessary, as the FAST output driver group is the last output driver group remaining after all other output driver groups are off.

As a result, one of the SLOW output driver group control signal, the TYP output driver group control signal, and the FAST output driver group control signal is high. In FIG. 16, each of the output driver groups is controlled by a corresponding one of the SLOW, TYP, and FAST output driver group control signals.

Other embodiments have more than 3 output driver groups and more than 3 output driver group control signals.

In another embodiment, each of the tri-state inverters in FIG. 18 is controlled by a corresponding one of the SLOW, TYP, and FAST output driver group control signals.

FIG. 18 is an example variable delay circuit for the output buffer of FIG. 16, responsive to the control signal circuit FIG. 17.

Signal IN is received by a plurality of delay circuits, which in one embodiment is a series of delay circuits, including delay circuit M 1804, delay circuit M-1 1806, and delay circuit 1 1808. Example delay circuits are delay elements such as a number of inverters. Tri-state buffer 1810

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has an input coupled to the series of delay circuits in between delay circuit M 1804 and delay circuit M-1 1806. Tri-state buffer 1812 has an input coupled to the series of delay circuits after delay circuit M-1 1806. Tri-state buffer 1814 has an input coupled to the series of delay circuits after delay circuit 1 1808. The outputs of tri-state buffers 1810, 1812, and 1814 are coupled to the output buffer 1816. Accordingly, the IN signal transits a variable number of delay circuits and undergoes a variable delay to reach the output buffer 1816, depending on the particular tri-state buffer transited by the IN signal.

In the embodiment of FIG. 18, the different sequential circuit groups of FIG. 15 generate control signals that undergo different amounts of delay. Tri-state buffers 1810, 1812, and 1814 are controlled by a corresponding one of the SLOW, TYP, and FAST output driver control signals from 1802, as discussed in FIG. 17. The FAST output driver control signal is received by tristate buffer 1814. The TYP output driver control signal is received by tristate buffer 1812. The SLOW output driver control signal is received by tristate buffer 1810.

The IN signal transits a maximum number of the delay circuits in order to reach tri-state buffer 1814. So in the case that the tri-state buffer 1814 is enabled by the FAST output driver control signal, the IN signal has undergone the maximum amount of delay prior to receipt by the tri-state buffer 1814 and subsequent receipt of the IN signal by the output buffer 1816.

The IN signal transits a minimum number of the delay circuits in order to reach tri-state buffer 1810. So in the case that the tri-state buffer 1810 is enabled by the SLOW output driver control signal, the IN signal has undergone the minimum amount of delay prior to receipt by the tri-state buffer 1810 and subsequent receipt of the IN signal by the output buffer 1816.

The IN signal transits an intermediate number of the delay circuits in order to reach tri-state buffer 1812. So in the case that the tri-state buffer 1812 is enabled by the TYP output driver control signal, the IN signal has undergone the intermediate amount of delay prior to receipt by the tri-state buffer 1812 and subsequent receipt of the IN signal by the output buffer 1816.

If the tclqv\_mimic signal has a relatively high value, the emulated buffer delay is relatively long, such that the output buffer is expected to be relatively slow unless corrected. Accordingly, the speed meter circuit measurement results in short amount of the variable delay so the combination of delays results in an actual output buffer delay having a more repeatable value despite variations in temperature, supply voltage, and/or process corner.

If the tclqv\_mimic signal has a relatively low value, the emulated buffer delay is relatively short, such that the output buffer is expected to be relatively fast unless corrected. Accordingly, the speed meter circuit measurement results in a lengthy amount of the variable delay so the combination of delays results in an actual output buffer delay having a more repeatable value despite variations in temperature, supply voltage, and/or process corner.

If the tclqv\_mimic signal has an intermediate value, the speed meter circuit measurement results in an intermediate amount of the variable delay so the combination of delays results in an actual output buffer delay having a more repeatable value despite variations in temperature, supply voltage, and/or process corner.

FIG. 19 is a chip diagram of an example integrated circuit 200. The integrated circuit 200 includes wiring terminals configured for connection to circuitry off of the integrated

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circuit 200, and wherein the output of the output buffer is connected to the wiring terminal. Wiring terminals can comprise pads for wire bonding to an IC package, “bumps” for flip chip bonding, through silicon via contacts for stacked ICs and the other terminals configured for connection to off-chip communications of the outputs of the output buffers. The integrated circuit 200 in this example, includes a memory array 1020 coupled to output buffers 260 via wiring 1040. In other examples, the integrated circuit may include processors, logic, analog circuits and so on, alone or in combination with other IC components. Circle 1090 illustrates that the output of an output buffer 260 is connected to a wiring terminal 1080.

The integrated circuit 200 includes a plurality of output buffers including the output buffer 260. The output buffers have output buffer delays adjustable in response to the control signals CTRL. The control signals CTRL are generated by control circuits 300 to control the plurality of output buffers. The control signals CTRL generated by one control circuit 300 may be applied to the set of control inputs of more than one of the output buffers in the plurality of output buffers. As shown in FIG. 2A, one control circuit 300 is coupled to one output buffer 260. In general, one control circuit 300 can be coupled to one or many output buffers 260. Further, the integrated circuit 200 can include multiple control circuits, each coupled to one or many output buffers. The number of output buffers coupled to a control circuit may be different from the number of output buffers coupled to another control circuit.

While the present technology is disclosed by reference to the preferred implementations and examples detailed above, it is to be understood that these examples are intended in an illustrative rather than in a limiting sense. It is contemplated that modifications and combinations will readily occur to those skilled in the art, which modifications and combinations will be within the spirit of the technology and the scope of the following claims. What is claimed is:

What is claimed is:

1. An integrated circuit comprising:

- an output buffer having an output buffer delay, a signal input and a signal output, the output buffer having a variable number of a plurality of output drivers that are on, in response to output driver control signals; and
- a plurality of sequential circuits receiving as input first and second timing signals, wherein relative timing of the first and second timing signals determines the variable number of output drivers;
- a control circuit: (i) using a first circuit to generate the first timing signal with a first delay, (ii) using a second circuit to generate the second timing signal with a second delay that correlates with the output buffer delay, (iii) using the plurality of sequential circuits to generate the output driver control signals, and (iv) causing the variable number of the plurality of output drivers to be on, in response to the output driver control signals.

2. The integrated circuit of claim 1, wherein the variable number of output drivers depends on a number of the sequential circuits transited by the second timing signal until the plurality of sequential circuits receive the first timing signal.

3. The integrated circuit of claim 1, wherein

- the first delay circuit responds to a reference signal to generate the first timing signal with the first delay, and wherein the first delay is substantially insensitive to at least one of process, voltage and temperature (PVT) conditions; and

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the second circuit responds to the reference signal on its input to generate the second timing signal on its output with the second delay, and wherein the second delay correlates with changes in the output buffer delay resulting from said at least one of process, voltage and temperature (PVT) conditions.

4. The integrated circuit of claim 1, wherein the plurality of output drivers are in parallel, and the output buffer delay is shortened or lengthened by the variable number of output drivers being more or less.

5. The integrated circuit of claim 1, wherein the plurality of output drivers are divided into a plurality of groups of output drivers, and a same sequential circuit driver in the plurality of sequential circuits controls different output drivers within a same group of the plurality of groups of output drivers.

6. The integrated circuit of claim 5, wherein the plurality of sequential circuits are divided into a plurality of groups of sequential circuits, and different sequential circuits in a same group of the plurality of groups of sequential circuits control the same group of the plurality of groups of output drivers.

7. The integrated circuit of claim 1, wherein the plurality of sequential circuits are divided into a plurality of groups of sequential circuits, and different sequential circuits in a same group of the plurality of groups of sequential circuits control a same output driver in the plurality of output drivers.

8. An integrated circuit comprising:

- an output buffer having an output buffer delay, a signal input and a signal output, and a control signal input receiving an output driver control signal;
- a plurality of sequential circuits receiving as input first and second timing signals, the first timing signal generated from a first delay circuit, the second timing signal generated with a second delay that correlates with the output buffer delay;
- a plurality of delay circuits generating a variable delay determining the output buffer delay, the variable delay depending on a number of the plurality of sequential circuits transited by the second timing signal until the plurality of sequential circuits receive the first timing signal;
- a control circuit: (i) using the first delay circuit to generate the first timing signal with a first delay, (ii) using a second delay circuit to generate the second timing signal with the second delay that correlates with the output buffer delay, (iii) using the plurality of sequential circuits to generate the output driver control signal, and (iv) causing the output driver control signal to undergo the variable delay in order to reach the output buffer.

9. The integrated circuit of claim 8, wherein

- the first delay circuit responds to a reference signal to generate the first timing signal with the first delay, and wherein the first delay is substantially insensitive to at least one of process, voltage and temperature (PVT) conditions; and

the second delay circuit responds to the reference signal to generate the second timing signal with the second delay, and wherein the second delay correlates with changes in the output buffer delay resulting from said at least one of process, voltage and temperature (PVT) conditions.

10. The integrated circuit of claim 8, wherein the plurality of sequential circuits are divided into a plurality of groups of sequential circuits, and a same delay is generated by the

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plurality of delay circuits responsive to different sequential circuits within a same group of the plurality of groups of sequential circuits.

11. The integrated circuit of claim 8, wherein the plurality of sequential circuits are divided into a plurality of groups of sequential circuits, and the variable delay is a same value caused by output driver signals generated from different sequential circuits within a same group of the plurality of groups of sequential circuits.

12. A method for controlling an output buffer, where the output buffer has an output buffer delay, comprising:

generating a first timing signal with a first delay;

generating a second timing signal with a second delay that correlates with the output buffer delay; and

adjusting a variable number of output drivers that are on in a plurality of output drivers in the output buffer, in response to a number of sequential circuits of a plurality of sequential circuits transited by the second timing signal upon receipt by the plurality of sequential circuits of the first timing signal.

13. The method of claim 12, including

using a reference delay circuit which responds to a reference signal to generate the first timing signal, and

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wherein the first delay is substantially insensitive to at least one of process, voltage and temperature (PVT) conditions; and

using a delay emulation circuit which responds to the reference signal to generate the second timing signal, and wherein the second delay correlates with changes in the output buffer delay resulting from said at least one of process, voltage and temperature (PVT) conditions.

14. The method of claim 12, wherein the output buffer comprises a plurality of parallel output drivers, and the output buffer delay is shortened or lengthened by the variable number of output drivers being more or less.

15. The method of claim 12, wherein the plurality of output drivers are divided into a plurality of groups of output drivers, and a same sequential circuit driver in the plurality of sequential circuits controls different output drivers within a same group of the plurality of groups of output drivers.

16. The method of claim 15, wherein the plurality of sequential circuits are divided into a plurality of groups of sequential circuits, and different sequential circuits drivers in a same group of the plurality of groups of sequential circuits control the same group of the plurality of groups of output drivers.

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